4/20/2008

RELIABILITY MONITOR REPORT
FOR

SAT 0.4µm Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX8695GELR+

The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 8720** **FITS: 13.1**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

Process Information:

Process Description: SAT 0.4µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE		MAX8695GELR+	135C, 5.25V	1000 HRS	45	0	
				Total:		**0**	

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